

IDS 7/25/03 1/2

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-2348	SERIAL NO. Unknown 10/627468
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Tyler A. Lowrey et al.	
				FILING DATE Filed herewith 7/25/03	GROUP Unknown 2812

*Examiner Initial	Document Number	Date	U.S. PATENT DOCUMENTS
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					Yes	No	
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JK	AH		Takeshi Hamamoto et al.; "Cell-Plate-Line and Bit-Line Complementarily Sensed (CBCS) Architecture for Ultra Low-Power Non-Destructive DRAMs"; 1995 Symposium on VLSI Circuits Digest of Technical Papers; pp. 79-80
JK	AI		Mikio Asakura et al.; "Cell-Plate Line Connecting Complementary Bitline (C ²) Architecture for Battery Operating DRAMs"; LSI Research and Development Laboratory; undated; pp. 59-60
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EXAMINER <i>James M. Kennedy</i>	DATE CONSIDERED <i>November 24, 2004</i>
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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Tyler A. Lowrey et al.				
				FILING DATE 7/25/03	GROUP 2812			
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	AR							
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EXAMINER		Jung M. Kennedy			DATE CONSIDERED			
					November 24, 2004			
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**U.S. DEPARTMENT OF COMMERCE
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MI22-2348

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APPLICANT
Tyler A. Lowrey et al.

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July 25, 2003

GROUP
2812

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						Yes	No
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AF							

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AK		
AL		

EXAMINER *Jeff M. Lennoy* **DATE CONSIDERED** *November 24, 2004*

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